

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1736		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Gurtel S. Sandhu et al.			
				FILING DATE Filed Herewith		GROUP	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
SWC	AA	4,558,509	✓	12/85	Tiwari		
	AB	4,568,565	✓	02/86	Gupta et al.		
	AC	5,023,683	✓	06/91	Yamada		
	AD	5,053,351	✓	10/91	Fazan et al.		
	AE	5,071,781	✓	12/91	Seo et al.		
	AF	5,130,172	✓	07/92	Hicks et al.		
	AG	5,139,825	✓	08/92	Gordon et al.		
	AH	5,168,073	✓	12/92	Gonzalez et al.		
	AI	5,216,267	✓	06/93	Jim et al.		
	AJ	5,223,729	✓	06/93	Kudo et al.		
SWC	AK	5,290,726	✓	03/94	Kan		
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AL						
	AN						
	AO						
	AP						
OTHER PRIOR ART (including Author, Title, Date, Pertinent Pages, Etc.)							
SWC	AR			Conrad, J.R. et al., "Ion Beam Assisted Coating And Surface Modification With Plasma Source Ion Implantation", J. Vac. Sci. Technol. A 8 (4), Jul/Aug. 1990, 3146-3151.			
SWC	AS			Temmler, D., "Multilayer Vertical Stacked Capacitors (MVSTC) for 64 Mbit and 256 mBit DRAMS", Article, Institute of Semiconductor Physics, Germany, no date, 2 pgs.			
SWC	AT			Niermer, B., et al., "Organometallic Chemical Vapor Deposition of Tungsten Metal, and Suppression of Carbon Incorporation by Codeposition of Platinum", Article, University of California, Los Angeles, CA, Dept. of Chemistry and Biochemistry, published 8/4/92, 3 pgs.			
EXAMINER CRANE				DATE CONSIDERED 2/18/04			
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SWC	AA	5,300,321	✓	04/94	Nakano et al.		
	AB	5,320,878	✓	06/94	Mays		
	AC	5,350,614	✓	07/94	Alm		
	AD	5,403,620	✓	04/95	Kanaz et al.		
	AE	5,508,218	✓	04/96	Jun		
	AF	5,006,481	✓	04/91	Chan et al.		
	AG	5,021,357		06/91	Taguchi et al.		
	AH	5,061,651	✓	10/91	Ito		
	AI	5,116,776	✓	05/92	Chan et al.		
	AJ	5,135,883	✓	08/92	Ban et al.		
	AK	5,164,337	✓	11/92	Ogawa et al.		
SWC	AL	5,170,233	✓	12/92	Liu et al.		
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							Yes No
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OTHER PRIOR ART (including Author, Title, Date, Pertinent Pages, Etc.)							
SWC	AR			T. Morihara et al., "Disk-Shaped Stacked Capacitor Cell for 256 Mb Dynamic Random-Access Memory", Aug. 19, 1994,			
				Jpn. J. Appl. Phys. Vol. 33 (1994), Pt. 1, No. 8, pp. 14-19			
SWC	AS			S. Woo et al., "Selective Etching Technology of <i>in-situ</i> P Doped Poly-Si (SEDOF) for High Density DRAM Capacitors",			
				1994 Symposium on VLSI Technology Digest of Technical Papers, pp. 25-26			
SWC	AT			H. Watanabe et al., "Stacked Capacitor Cells for High-density dynamic RAMs", IEDM 1985, pp. 600-603			
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SWC	AA	5,622,882	✓	04/97	Yee		
	AB	5,631,184	✓	05/97	Ikegami et al.		
	AC	6,025,248	✓	02/00	Kim et al.		
	AD	5,930,640	✓	07/99	Kenney		
	AE	5,464,786	✓	11/95	Figure et al.		
	AF	5,968,686	✓	10/99	Yamada et al.		
	AG	5,953,254	✓	09/99	Pourkaramali		
	AH	5,952,688	✓	09/99	Madan		
	AI	5,945,704	✓	08/99	Schrems et al.		
	AJ	5,907,170	✓	05/99	Porbes et al.		
SWC	AK	5,005,072	✓	04/91	Gonzalez		
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	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
SWC	AR			Inoue, S., et al., "A Spread Stacked Capacitor (SCC) Cell for 64MBIT DRAMs", IEEE 1989, pp. 31-34 (2.3.1 - 2.3.4).			
SWC	AS			Ema, T. et al., "3-Dimensional Stacked Capacitor Cell for 16M And 64M DRAMs," MOS Division, Fujitsu Limited, IEEE 1988, pp. 592-595.			
SWC	AT			Wolf, S. et al., "Silicon Processing for the VLSI Era," 1986, Lattice Press, p. 493.			
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SWC	AA	4,742,018	✓	05/88	Kimura et al.			
	AB	5,103,275	✓	04/92	Miura et al.			
	AC	5,677,222	✓	10/97	Tsang			
	AD	5,160,987	✓	11/92	Pricer et al.			
	AE	5,684,316	✓	11/97	Lee			
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
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